

SPECIFICATION

Please amend the Specification as follows:

[0001] (Amended) This is a division of [[pending]] application Serial No. 10/243,073 filed 13 September 2002, now U.S. Patent 6,659,639, which is a continuation application of [[pending]] application Serial No. 09/843,927 filed 30 April 2001, now U.S. Patent 6,540,398 issued April 1, 2003, which is a division of U.S. Serial No. 09/145,549 filed 02 September 1998, now U.S. Patent 6,267,500, which is a division of U.S. Serial No. 08/848,012 filed 28th April 1997 and now U.S. Patent 5,823,679 issued 20th October 1998, which [[U.S. Serial No. 08/843,927]] is a continuation-in-part application of both United States applications Serial Nos. 08/764,659 filed on 11th December 1996, now U.S. Patent 5,823,678, and 08/617,265 filed on 18th March 1996, now U.S. Patent 5,727,880, in the names of Milton B. Hollander and W. Earl McKinley for Method and Apparatus for Measuring Temperature Using Infrared Techniques, the latter of which, is a continuation-in-part of United States application Serial No. 08/348,978 filed on 28th November 1994, now U.S. Patent 5,524,984 which in turn was a continuation[-in-part] application of then copending United States patent application Serial No. 08/121,916 filed 17th September 1993, now issued as United States Patent 5,368,392 on 29th November 1994.